

substance: titanium oxide (TiO₂)

property: transport properties in non-stoichiometric TiO_{2-x}: resistivity vs. T^{-1}

Above 300 K (Fig. 1) samples with oxygen deficiencies in the critical range $1.8 \cdot 10^{19} \text{ cm}^{-3} < O_d < 2 \cdot 10^{20} \text{ cm}^{-3}$ exhibit three distinct temperature regions: Region "a" having an independent $E_A^a = 0.028 \text{ eV}$, region "b" having an O_d -dependent $E_A^b = E_0 + \beta O_d^{1/3}$ with $E_0 \approx 0.0080 \text{ eV}$ and $\beta \approx 8.8 \cdot 10^{-9} \text{ eV cm}$, and an exhaustion region "c" [74I]. Typical data for such samples, obtained by measurements in the [110] direction, are given in the following table (cf. Fig. 1) [74I]:

Specimen	1	2	3	4	5	6
Reduction (temperature [K] · time [h])		1073 · 368		1173 · 160	1073 · 368	1173 · 160
	1073 · 368	+	1173 · 160	+	1173 · 164	1273 · 45
		1173 · 164		1273 · 45	+	+
					1273 · 230	1373 · 40
Exhaustion temperature [K]	≈ 900	≈ 1000	≈ 1000	≈ 1100	≈ 1100	≈ 1200
ρ [$\Omega \text{ cm}$] in exhaustion range	2.76	1.60	1.06	0.91	0.71	0.50
μ [$\text{cm}^2/\text{V s}$] in exhaustion range	$6.42 \cdot 10^{-2}$	$4.93 \cdot 10^{-2}$	$4.93 \cdot 10^{-2}$	$3.89 \cdot 10^{-2}$	$3.89 \cdot 10^{-2}$	$3.12 \cdot 10^{-2}$
Concentration of electrons, n [cm^{-3}]	$3.5 \cdot 10^{19}$	$7.9 \cdot 10^{19}$	$1.2 \cdot 10^{20}$	$1.8 \cdot 10^{20}$	$2.3 \cdot 10^{20}$	$4.00 \cdot 10^{20}$
Concentration of deficient oxygens, O_d [cm^{-3}]	$1.8 \cdot 10^{19}$	$4.0 \cdot 10^{19}$	$6.0 \cdot 10^{19}$	$8.8 \cdot 10^{19}$	$1.1 \cdot 10^{20}$	$2.00 \cdot 10^{20}$

The peculiar increase in E_A with increasing O_d appears to reflect a clustering of donor centres, i.e. the condensation of $(\text{Ti}_i^{3\cdot})_2$ into $(\text{Ti}^{3+} - \text{Ti}^{3+})$ APB's of increasing area. Hall measurements on single crystal samples cut perpendicular to the c -axis also showed a change from simple to complex behaviour with increasing O_d suggestive of defect clustering at the higher concentrations [64A].

At high oxygen partial pressures, it is necessary to take into account the influence of impurities (see second next document).

It seems reasonably well established [76B, 77B1, 77B2], that at elevated temperatures, the onset of diphasic behaviour occurs at a somewhat larger value of x than suggested by low-temperature EPR and electron microscopy data. Thus the apparent success of point defect models for TiO₂ at $T > 1300 \text{ K}$ [67K] for values of x as high as 0.01 can be understood on this basis.

References:

- 59G Grant, F. A.: Rev. Mod. Phys. 31 (1959) 646.
- 64A Acket, G. A., Volger, J.: Phys. Lett. 8 (1964) 244.
- 67K Kofstad, P.: J. Less-Common Met. 13 (1967) 635.
- 74I Iguchi, E., Yagima, K., Asahima, T., Kanamori, T.: J. Phys. Chem. Solids 35 (1974) 597.
- 76B Baumard, J. F.: Solid State Commun. 20 (1976) 859.
- 77B1 Baumard, J. F., Panis, D., Anthony, A. M.: J. Solid State Chem. 20 (1977) 43.
- 77B2 Baumard, J. F., Gervais, E.: Phys. Rev. B 15 (1977) 2316.

Fig. 1.

TiO_2 . (a) Resistivity in the $[110]$ direction of moderately reduced TiO_2 vs. reciprocal temperature, (b) dependence of activation energy in ranges a and b on oxygen deficiency. For data on the samples 1...6, see the tables [59G, 74I].

